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### **Embedded - System On Chip (SoC): The Heart of Modern Embedded Systems**

**Embedded - System On Chip (SoC)** refers to an integrated circuit that consolidates all the essential components of a computer system into a single chip. This includes a microprocessor, memory, and other peripherals, all packed into one compact and efficient package. SoCs are designed to provide a complete computing solution, optimizing both space and power consumption, making them ideal for a wide range of embedded applications.

### **What are Embedded - System On Chip (SoC)?**

**System On Chip (SoC)** integrates multiple functions of a computer or electronic system onto a single chip. Unlike traditional multi-chip solutions, SoCs combine a central

#### **Details**

Product Status	Active
Architecture	MCU, FPGA
Core Processor	ARM® Cortex®-M3
Flash Size	256KB
RAM Size	64KB
Peripherals	DDR, PCIe, SERDES
Connectivity	CANbus, Ethernet, I <sup>2</sup> C, SPI, UART/USART, USB
Speed	166MHz
Primary Attributes	FPGA - 60K Logic Modules
Operating Temperature	-55°C ~ 125°C (TJ)
Package / Case	484-BGA
Supplier Device Package	484-FPBGA (23x23)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/microchip-technology/m2s060t-1fgg484m">https://www.e-xfl.com/product-detail/microchip-technology/m2s060t-1fgg484m</a>

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**Table 3 • Recommended Operating Conditions (continued)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units	Notes
PLL0_PLL1_HPMS_MDDR_VDDA	Analog power pad for MDDR PLL	2.5 V Range	2.375	2.5	2.625	V	–
		3.3 V Range	3.15	3.3	3.45	V	–
CCC_XX[01]_PLL_VDDA	Analog power pad for PLL0-5	2.5 V Range	2.375	2.5	2.625	V	–
		3.3 V Range	3.15	3.3	3.45	V	–
SERDES_[01]_PLL_VDDA	High supply voltage for PLL SERDES[01]	2.5 V Range	2.375	2.5	2.625	V	2
		3.3 V Range	3.15	3.3	3.45	V	2
SERDES_[01]_L[0123]_VDDAPLL	Analog power for SERDES[01] PLL lanes 0-3. It is a +2.5 V SERDES internal PLL supply.	–	2.375	2.5	2.625	V	–
SERDES_[01]_L[0123]_VDDAIO	TX/RX analog I/O voltage. Low voltage power for the lanes of SERDESIF0. It is a +1.2 V SERDES PMA supply.	–	1.14	1.2	1.26	V	–
SERDES_[01]_VDD	PCIe/PCS Power supply	–	1.14	1.2	1.26	V	–
VDDIx	1.2 V DC supply voltage	–	1.14	1.2	1.26	V	–
	1.5 V DC supply voltage	–	1.425	1.5	1.575	V	–
	1.8 V DC supply voltage	–	1.71	1.8	1.89	V	–
	2.5 V DC supply voltage	–	2.375	2.5	2.625	V	–
	3.3 V DC supply voltage	–	3.15	3.3	3.45	V	–
	LVDS differential I/O	–	2.375	2.5	3.45	V	–
	BLVDS, MLVDS, Mini-LVDS, RSDS differential I/O	–	2.375	2.5	2.625	V	–
VREFx	Reference Voltage Supply for FDDR (Bank0) and MDDR(Bank5)	–	$0.49 \times$	$0.5 \times$	$0.51 \times$	V	–
			VDDIx	VDDIx	VDDIx		

**Table 3 • Recommended Operating Conditions (continued)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units	Notes
VPPNVM	Analog sense circuit supply of embedded nonvolatile memory (eNVM). Must be shorted to VPP	2.5 V Range	2.375	2.5	2.625	V	–
		3.3 V Range	3.15	3.3	3.45	V	–
<i>Notes:</i> 1. Programming at this temperature range is available only with VPP in 3.3 V Range 2. Power supply ramps must all be strictly monotonic, without plateaus.							

**Table 4 • FPGA Operating Limits**

Product Grade	Element	Programming Temperature	Operating Temperature	Programming Cycles	Retention (Biased/Unbiased)	Note
Military	FPGA	Min T <sub>J</sub> = 0°C Max T <sub>J</sub> = 85°C	Min T <sub>J</sub> = -55°C Max T <sub>J</sub> = 125°C	500	10 Years	–
		Min T <sub>J</sub> = -40°C Max T <sub>J</sub> = 100°C	Min T <sub>J</sub> = -55°C Max T <sub>J</sub> = 125°C	500	10 Years	*
<i>Note:</i> *: Programming at this temperature range is available only with VPP in 3.3 V Range						

**Table 5 • Embedded Flash Limits**

Product Grade	Element	Programming Temperature	Maximum Operating Temperature	Programming Cycles	Retention (Biased/Unbiased)
Military	Embedded flash	Min T <sub>J</sub> = -55°C Max T <sub>J</sub> = 125°C	Min T <sub>J</sub> = -55°C Max T <sub>J</sub> = 125°C	< 10,000 cycles per pages, up to one million cycles per eNVM array	10 Years

**Table 6 • Device Storage Temperature and Retention**

Product Grade	Storage Temperature (Tstg)	Retention
Military	Min T <sub>J</sub> = -55°C Max T <sub>J</sub> = 125°C	10 Years

## 4.2 Overshoot/Undershoot Limits

For AC signals, the input signal may undershoot during transitions to -1.0 V for no longer than 10% or the period. The current during the transition must not exceed 100mA.

For AC signals, the input signal may overshoot during transitions to VCCI + 1.0 V for no longer than 10% of the period. The current during the transition must not exceed 100mA.

Note: The above specification does not apply to the PCI standard. The IGLOO2 and SmartFusion2 PCI I/Os are compliant to the PCI standard including the PCI overshoot/undershoot specifications.

## 8.4 I/O Speeds

**Table 16 • Maximum Data Rate Summary for Worst-Case Military Conditions**

<b>Single-Ended I/O</b>	<b>MSIO</b>	<b>MSIOD</b>	<b>DDRIO</b>	<b>Units</b>
PCI 3.3 V	560	–	–	Mbps
LVTTL 3.3 V	540	–	–	Mbps
LVC MOS 3.3 V	540	–	–	Mbps
LVC MOS 2.5 V	360	370	360	Mbps
LVC MOS 1.8 V	260	360	360	Mbps
LVC MOS 1.5 V	140	190	210	Mbps
LVC MOS 1.2 V	100	140	180	Mbps
LPDDR – LVC MOS 1.8 V Mode	–	–	360	Mbps
<b>Voltage-Referenced I/O</b>	<b>MSIO</b>	<b>MSIOD</b>	<b>DDRIO</b>	<b>Units</b>
LPDDR	–	–	360	Mbps
HSTL 1.5 V	–	–	360	Mbps
SSTL 2.5 V	450	480	360	Mbps
SSTL 1.8 V	–	–	600	Mbps
<b>Voltage-Referenced I/O</b>	<b>MSIO</b>	<b>MSIOD</b>	<b>DDRIO</b>	<b>Units</b>
SSTL 1.5 V	–	–	600	Mbps
<b>Differential I/O</b>	<b>MSIO</b>	<b>MSIOD</b>	<b>DDRIO</b>	<b>Units</b>
LVPECL (input only)	810	–	–	Mbps
LVDS 3.3 V	480	480	–	Mbps
LVDS 2.5 V	480	480	–	Mbps
RS DS	460	480	–	Mbps
BLVDS	450	–	–	Mbps
MLVDS	450	–	–	Mbps
Mini-LVDS	460	480	–	Mbps

## 8.6.4 1.8 V LVCMOS

LVCMOS 1.8 is a general standard for 1.8 V applications and is supported in IGLOO2 FPGAs and SmartFusion2 SoC FPGAs in compliance to the JEDEC specification JESD8-7A.

### 8.6.4.1 Minimum and Maximum AC/DC Input and Output Levels

**Table 33 • LVCMOS 1.8 V DC Voltage Specification**

Symbols	Parameters	Min	Typ	Max	Units
<b>Recommended DC Operating Conditions</b>					
VDDI	Supply Voltage	1.710	1.8	1.89	V
<b>LVCMOS 1.8 V DC Input Voltage Specification</b>					
VIH(DC)	DC input Logic HIGH (for MSIOD and DDRIO I/O Banks)	0.65 x VDDI	–	1.89	V
VIH(DC)	DC input Logic HIGH (for MSIO I/O Bank)	0.65 x VDDI	–	2.75	V
VIL(DC)	DC input Logic LOW	-0.3	–	0.35 x VDDI	V
IIH(DC)	Input Current HIGH	–	–	10	uA
IIL(DC)	Input Current LOW	–	–	10	uA
<b>LVCMOS 1.8 V DC Output Voltage Specification</b>					
VOH	DC output Logic HIGH	VDDI - 0.45	–	–	V
VOL	DC output Logic LOW	–	–	0.45	V

**Table 34 • LVCMOS 1.8 V Maximum AC Switching Speeds**

Symbols	Parameters	Conditions	Min	Typ	Max	Units
<b>LVCMOS 1.8 V Maximum AC Switching Speed</b>						
Dmax	Maximum data rate (for DDRIO I/O Bank)	AC loading: 17 pF load, maximum drive/slew	–	–	360	Mbps
Dmax	Maximum data rate (for MSIO I/O Bank)	AC loading: 17 pF load, maximum drive/slew	–	–	260	Mbps
Dmax	Maximum data rate (for MSIOD I/O Bank)	AC loading: 17 pF load, maximum drive/slew	–	–	360	Mbps
<i>Note: * Maximum data rate applies for drive strength 8mA and above, all slews</i>						

**Table 35 • LVCMOS 1.8 V Transmitter Drive Strength Specifications**

Output Drive Selection		VOH (V)	VOL (V)	IOH (at VOH) mA	IOL (at VOL) mA
MSIO I/O Bank	MSIOD I/O Bank	Min	Max		
2 mA	2 mA	VDDI – 0.45	0.45	2	2
4 mA	4 mA	VDDI – 0.45	0.45	4	4
6 mA	6 mA	VDDI – 0.45	0.45	6	6
8 mA	8 mA	VDDI – 0.45	0.45	8	8
10 mA	10 mA	VDDI – 0.45	0.45	10	10
12 mA	N/A	VDDI – 0.45	0.45	12	12

**Table 41 • LVC MOS 1.5 V Maximum AC Switching Speeds**

Symbols	Parameters	Conditions	Min	Typ	Max	Units
<b>LVC MOS 1.5 V Maximum AC Switching Speed</b>						
Dmax	Maximum data rate (for DDRIO I/O Bank)	AC loading: 17 pF load, maximum drive/slew	–	–	210	Mbps
Dmax	Maximum data rate (for MSIO I/O Bank)	AC loading: 17 pF load, maximum drive/slew	–	–	140	Mbps
Dmax	Maximum data rate (for MSIOD I/O Bank)	AC loading: 17 pF load, maximum drive/slew	–	–	190	Mbps

**Table 42 • LVC MOS 1.5 V AC Test Parameters and Driver Impedance Specifications**

Symbols	Parameters	Conditions	Min	Typ	Max	Units
<b>LVC MOS 1.5 V AC Calibrated Impedance Option</b>						
Rodt_cal	Supported output driver calibrated impedance (for DDRIO I/O Bank)		–	75, 60, 50, 40	–	$\Omega$
<b>LVC MOS 1.5 V AC Test Parameters Specifications</b>						
Vtrip	Measuring/trip point for data path		–	0.75	–	V
Rent	Resistance for enable path ( $t_{ZH}$ , $t_{ZL}$ , $t_{HZ}$ , $t_{LZ}$ )		–	2k	–	$\Omega$
Cent	Capacitive loading for enable path ( $t_{ZH}$ , $t_{ZL}$ , $t_{HZ}$ , $t_{LZ}$ )		–	5	–	pF
Cload	Capacitive loading for data path ( $t_{DP}$ )		–	5	–	pF

**Table 43 • LVC MOS 1.5 V Transmitter Drive Strength Specifications**

Output Drive Selection			VOH (V)	VOL (V)	IOH (at VOH) mA	IOL (at VOL) mA
MSIO I/O Bank	MSIOD I/O Bank	DDRIO I/O Bank (with Fixed Code)	Min	Max		
2 mA	2 mA	2 mA	VDDI × 0.75	VDDI × 0.25	2	2
4 mA	4 mA	4 mA	VDDI × 0.75	VDDI × 0.25	4	4
6 mA	6 mA	6 mA	VDDI × 0.75	VDDI × 0.25	6	6
8 mA	N/A	8 mA	VDDI × 0.75	VDDI × 0.25	8	8
N/A	N/A	10 mA	VDDI × 0.75	VDDI × 0.25	10	10
N/A	N/A	12 mA	VDDI × 0.75	VDDI × 0.25	12	12

**AC Switching Characteristics for Transmitter (Output and Tristate Buffers)**
**Table 59 • HSTL 15 AC Switching Characteristics for Transmitter (Output and Tristate Buffers)**  
 Worst-Case Military Conditions:  $T_J = 125^{\circ}\text{C}$ ,  $V_{DD} = 1.14\text{ V}$ ,  $V_{DDI} = 1.425\text{ V}$ 

	Speed Grade -1					Units
	$t_{DP}$	$t_{ZL}$	$t_{ZH}$	$t_{HZ}$	$t_{LZ}$	
<b>HSTL Class I (for DDRIO I/O Bank)</b>						
Single Ended	2.922	2.91	2.904	3.225	3.218	ns
Differential	2.907	2.757	2.755	2.662	2.66	ns
<b>HSTL Class II (for DDRIO I/O Bank)</b>						
Single Ended	2.817	2.735	2.735	2.644	2.644	ns
Differential	2.827	2.81	2.803	3.205	3.197	ns

**8.7.2 Stub-Series Terminated Logic**

Stub-Series Terminated Logic (SSTL) for 2.5 V (SSTL2), 1.8 V (SSTL18), and 1.5 V (SSTL15) is supported in IGLOO2 and SmartFusion2 SoC FPGAs. SSTL2 is defined by JEDEC standard JESD8-9B and SSTL18 is defined by JEDEC standard JESD8-15. IGLOO2 SSTL I/O configurations are designed to meet double data rate standards DDR/2/3 for general purpose memory buses. Double data rate standards are designed to meet their JEDEC specifications as defined by JEDEC standard JESD79F for DDR, JEDEC standard JESD79-2F for DDR, JEDEC standard JESD79-3D for DDR3, and JEDEC standard JESD209A for LPDDR.

**8.7.3 Stub-Series Terminated Logic 2.5 V (SSTL2)**

SSTL2 Class I and Class II are supported in IGLOO2 and SmartFusion2 SoC FPGAs and also comply with reduced and full drive of double data rate (DDR) standards. IGLOO2 and SmartFusion2 SoC FPGA I/Os supports both standards for single-ended signaling and differential signaling for SSTL2. This standard requires a differential amplifier input buffer and a push-pull output buffer.

**8.7.3.1 Minimum and Maximum DC Input and Output Levels Specification**
**Table 60 • DDR1/SSTL2 Minimum and Maximum DC Input and Output Levels**

Symbols	Parameters	Conditions	Min	Typ	Max	Units
<b>Recommended DC Operating Conditions</b>						
VDDI	Supply voltage		2.375	2.5	2.625	V
VTT	Termination voltage		1.164	1.250	1.339	V
VREF	Input reference voltage		1.164	1.250	1.339	V
<b>SSTL2 DC Input Voltage Specification</b>						
VIH (DC)	DC input logic High		$V_{REF} + 0.15$	–	2.625	V
VIL (DC)	DC input logic Low		–0.3	–	$V_{REF} - 0.15$	V
I <sub>IH</sub> (DC)	Input current High		–	–	10	μA
I <sub>IL</sub> (DC)	Input current Low		–	–	10	μA
<b>SSTL2 DC Output Voltage Specification</b>						
<b>SSTL2 Class I (DDR Reduced Drive)</b>						
VOH	DC output logic High		$V_{TT} + 0.608$	–	–	V
VOL	DC output logic Low		–	–	$V_{TT} - 0.608$	V
IOH at VOH	Output minimum source DC current		8.1	–	–	mA



**Table 64 • DDR2/SSTL18 AC/DC Minimum and Maximum Input and Output Levels Specification (continued)**

Symbols	Parameters	Conditions	Min	Typ	Max	Units	Notes
IOL at VOL	Output minimum sink current (DDRIO I/O Bank only)		-12.0	-	-	mA	-
<b>SSTL18 DC Differential Voltage Specification</b>							
VID (DC)	DC input differential voltage		0.3	-	-	V	-
Note: *To meet JEDEC Electrical Compliance, use DDR2 Full Drive Transmitter.							

**Table 65 • DDR2/SSTL18 AC Specifications (Applicable to DDRIO Bank Only)**

Symbols	Parameters	Conditions	Min	Typ	Max	Units
<b>SSTL18 AC Differential Voltage Specification</b>						
VDIFF (AC)	AC input differential voltage		0.5	-	-	V
Vx (AC)	AC differential cross point voltage		$0.5 \times VDDI - 0.175$	-	$0.5 \times VDDI + 0.175$	V
<b>SSTL18 Maximum AC Switching Speed</b>						
Dmax	Maximum data rate (for DDRIO I/O Bank)	AC loading: per JEDEC specification	-	-	600	Mbps
<b>SSTL18 Impedance Specifications</b>						
Rref	Supported output driver calibrated impedance (for DDRIO I/O Bank)	Reference resistor = 150 $\Omega$	-	20, 42	-	$\Omega$
RTT	Effective impedance value (ODT)	Reference resistor = 150 $\Omega$	-	50, 75, 150	-	$\Omega$
<b>SSTL18 AC Test Parameters Specifications</b>						
Vtrip	Measuring/trip point for data path		-	0.9	-	V
Rent	Resistance for enable path ( $t_{ZH}$ , $t_{ZL}$ , $t_{HZ}$ , $t_{LZ}$ )		-	2k	-	$\Omega$
Cent	Capacitive loading for enable path ( $t_{ZH}$ , $t_{ZL}$ , $t_{HZ}$ , $t_{LZ}$ )		-	5	-	pF
Rtt_test	Reference resistance for data test path for SSTL18 Class I ( $t_{DP}$ )		-	50	-	$\Omega$
Rtt_test	Reference resistance for data test path for SSTL18 Class II ( $t_{DP}$ )		-	25	-	$\Omega$
Cload	Capacitive loading for data path ( $t_{DP}$ )		-	5	-	pF

**Table 78 • LPDDR-LVCMOS 1.8 V Maximum AC Switching Speeds (Applicable to DDRIO I/O Bank Only)**

Symbols	Parameters	Conditions	Min	Typ	Max	Units
Dmax	Maximum Data Rate (for DDRIO I/O Bank)	AC Loading: 17pF Load, 8mA Drive and Above/All Slew	–	–	360	Mbps

**Table 79 • LPDDR-LVCMOS 1.8 V AC Test Parameters and Driver Impedance Specifications (Applicable to DDRIO I/O Bank Only)**

Symbols	Parameters	Conditions	Min	Typ	Max	Units
<b>LPDDR - LVCMOS 1.8 V Calibrated Impedance Option</b>						
Rodt_cal	Supported Output Driver Calibrated Impedance (for DDRIO I/O Bank)	–	–	75, 60, 50, 33, 25, 20	–	Ω
<b>LPDDR- LVCMOS 1.8 V AC Test Parameters Specifications</b>						
Vtrip	Measuring/Trip Point for Data Path	–	–	0.9	–	V
Rent	Resistance for Enable Path (t <sub>ZH</sub> , t <sub>ZL</sub> , t <sub>HZ</sub> , t <sub>LZ</sub> )	–	–	2k	–	Ω
Cent	Capacitive Loading for Enable Path (t <sub>ZH</sub> , t <sub>ZL</sub> , t <sub>HZ</sub> , t <sub>LZ</sub> )	–	–	5	–	pF
Cload	Capacitive Loading for Data Path (t <sub>DP</sub> )	–	–	5	–	pF

**Table 80 • LPDDR-LVCMOS 1.8 V Mode Transmitter Drive Strength Specification (Applicable to DDRIO I/O Bank Only)**

Output Drive Selection	VOH (V) Min	VOL (V) Max	IOH (at VOH) mA	IOL (at VOL) mA	Notes
2 mA	VDDI – 0.45	0.45	2	2	–
4 mA	VDDI – 0.45	0.45	4	4	–
6 mA	VDDI – 0.45	0.45	6	6	–
8 mA	VDDI – 0.45	0.45	8	8	–
10 mA	VDDI – 0.45	0.45	10	10	–
12 mA	VDDI – 0.45	0.45	12	12	–
16 mA	VDDI – 0.45	0.45	16	16	*

Note: \* 16mA Drive Strengths, All Slews, meet LPDDR JEDEC electrical compliance

#### 8.7.6.4 AC Switching Characteristics

**Table 81 • LPDDR - LVCMOS 1.8 V AC Switching Characteristics for Receiver (Input Buffers)**

Worst-Case Military Conditions: T<sub>J</sub> = 125°C, VDD = 1.14 V, VDDI = 1.71 V

	ODT (On Die Termination)	Speed Grade –1		Units
		t <sub>py</sub>	t <sub>pys</sub>	
LPDDR-LVCMOS 1.8 mode (for DDRIO I/O Bank with Fixed Codes)	None	2.071	2.213	ns

### 8.8.2.2. AC Switching Characteristics

#### AC Switching Characteristics for Receiver (Input Buffers)

**Table 91 • B-LVDS AC Switching Characteristics for Receiver (Input Buffers)**

Worst-Case Military Conditions:  $T_J = 125^\circ\text{C}$ ,  $V_{DD} = 1.14\text{ V}$ ,  $V_{DDI} = 2.375\text{ V}$

	On-Die Termination (ODT)	Speed Grade -1	Units
		$t_{PY}$	
Bus-LVDS (for MSIO I/O Bank)	None	3.011	ns
	100	3.006	ns
Bus-LVDS (for MSIOD I/O Bank)	None	2.722	ns
	100	2.725	ns

AC Switching Characteristics for Transmitter (Output and Tristate Buffers)

**Table 92 • B-LVDS AC Switching Characteristics for Transmitter (Output and Tristate Buffers)**

Worst-Case Military Conditions:  $T_J = 125^\circ\text{C}$ ,  $V_{DD} = 1.14\text{ V}$ ,  $V_{DDI} = 2.375\text{ V}$

	Speed Grade -1					Units
	$t_{DP}$	$t_{ZL}$	$t_{ZH}$	$t_{HZ}$	$t_{LZ}$	
Bus-LVDS (for MSIO I/O Bank)	2.78	2.632	2.617	2.448	2.436	ns

### 8.8.3 M-LVDS

M-LVDS specifications extend the existing LVDS standard to high-performance multipoint bus applications. Multidrop and multipoint bus configurations may contain any combination of drivers, receivers, and transceivers.

#### 8.8.3.1 Minimum and Maximum Input and Output Levels

**Table 93 • M-LVDS DC Voltage Specification**

Symbols	Parameters	Conditions	Min	Typ	Max	Units	Notes
<b>M-LVDS Recommended DC Operating Conditions</b>							–
V <sub>DDI</sub>	Supply voltage		2.375	2.5	2.625	V	*
<b>M-LVDS DC Input Voltage Specification</b>							–
V <sub>I</sub>	DC input voltage		0	–	2.925	V	–
I <sub>IH</sub> (DC)	Input current High		–	–	10	μA	–
I <sub>IL</sub> (DC)	Input current Low		–	–	10	μA	–
<b>M-LVDS DC Output Voltage Specification (for MSIO I/O Bank Only)</b>							–
V <sub>OH</sub>	DC output logic High		1.25	1.425	1.6	V	–
V <sub>OL</sub>	DC output logic Low		0.9	1.075	1.25	V	–
<b>M-LVDS Differential Voltage Specification</b>							–
V <sub>OD</sub>	Differential output voltage Swing (for MSIO I/O Bank only)		300	–	650	mV	–
V <sub>OCM</sub>	Output common mode voltage (for MSIO I/O Bank only)		0.3	–	2.1	V	–
V <sub>ICM</sub>	Input common mode voltage		0.3	–	1.2	V	–

### 8.8.4 Mini-LVDS

Mini-LVDS is an unidirectional interface from the timing controller to the column drivers and is designed to the Texas Instruments Standard SLDA007A.

#### 8.8.4.1 Mini-LVDS Minimum and Maximum Input and Output Levels

**Table 97 • Mini-LVDS DC Voltage Specification**

Symbols	Parameters	Conditions	Min	Typ	Max	Units
<b>Recommended DC Operating Conditions</b>						
VDDI	Supply voltage		2.375	2.5	2.625	V
<b>Mini-LVDS DC Input Voltage Specification</b>						
VI	DC Input voltage		0	–	2.925	V
<b>Mini-LVDS DC Output Voltage Specification</b>						
VOH	DC output logic High		1.25	1.425	1.6	V
VOL	DC output logic Low		0.9	1.075	1.25	V
<b>Mini-LVDS Differential Voltage Specification</b>						
VOD	Differential output voltage swing		300	–	600	mV
VOCM	Output common mode voltage		1	–	1.4	V
VICM	Input common mode voltage		0.3	–	1.2	V
VID	Input differential voltage		100	–	600	mV

**Table 98 • Mini-LVDS AC Specifications**

Symbols	Parameters	Conditions	Min	Typ	Max	Units
<b>Mini-LVDS Maximum AC Switching Speed</b>						
Dmax	Maximum data rate (MSIO I/O Bank)	AC loading: 2 pF / 100 $\Omega$ differential load	–	–	460	Mbps
Dmax	Maximum data rate (MSIOD I/O Bank)	AC loading: 10 pF / 100 $\Omega$ differential load	–	–	480	Mbps
<b>Mini-LVDS Impedance Specification</b>						
Rt	Termination resistance		–	100	–	$\Omega$
<b>Mini-LVDS AC Test Parameters Specifications</b>						
VTrip	Measuring/trip point for data path		–	Cross point	–	V
Rent	Resistance for enable path ( $t_{ZH}$ , $t_{ZL}$ , $t_{HZ}$ , $t_{LZ}$ )		–	2k	–	$\Omega$
Cent	Capacitive loading for enable path ( $t_{ZH}$ , $t_{ZL}$ , $t_{HZ}$ , $t_{LZ}$ )		–	5	–	pF

### 8.8.4.2 AC Switching Characteristics

AC Switching Characteristics for Receiver (Input Buffers)

**Table 99 • Mini-LVDS AC Switching Characteristics for Receiver (Input Buffers)**

Worst-case Military Conditions:  $T_J = 125^\circ\text{C}$ ,  $V_{DD} = 1.14\text{ V}$ ,  $V_{DDI} = 2.375\text{ V}$

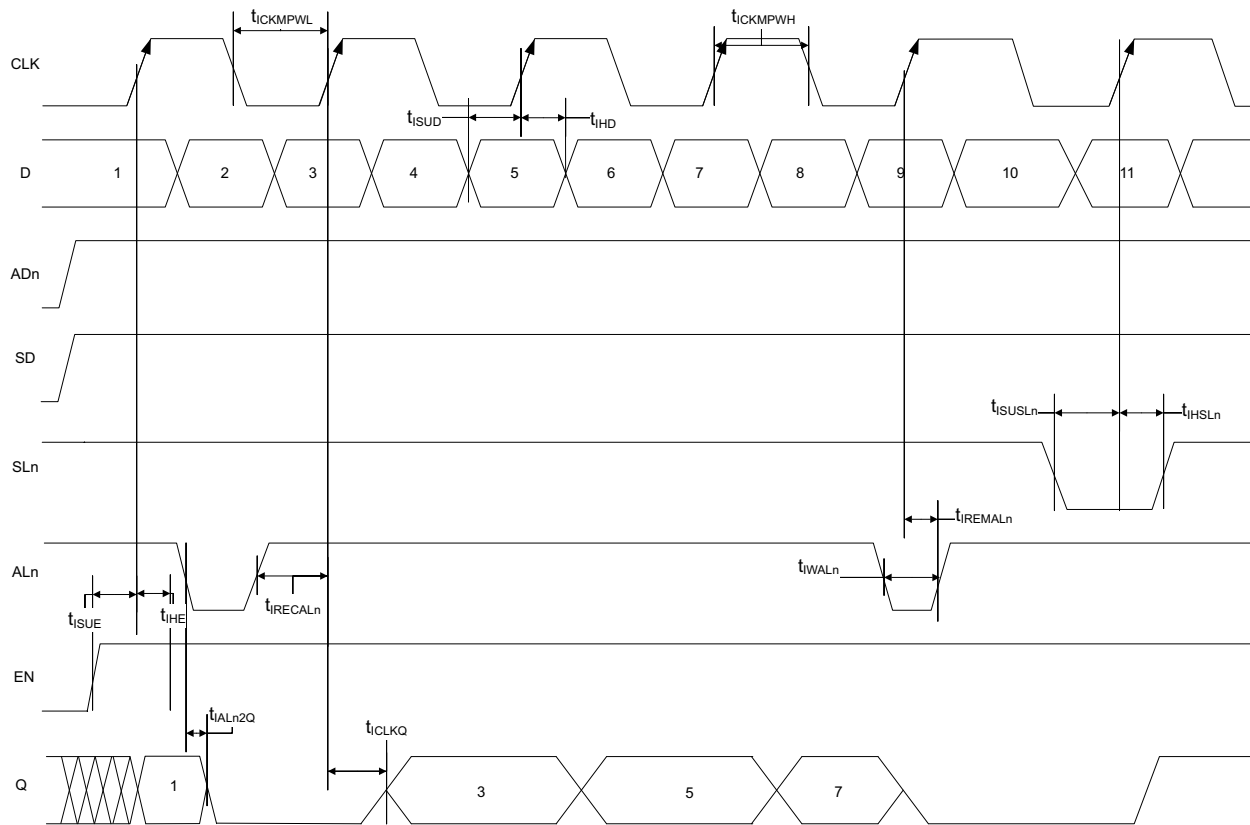
	On-Die Termination (ODT)	Speed Grade -1	Units
		$t_{pY}$	
Mini-LVDS (for MSIO I/O Bank)	None	3.112	ns
	100	2.995	ns
Mini-LVDS (for MSIOD I/O Bank)	None	2.612	ns
	100	2.612	ns

AC Switching Characteristics for Transmitter (Output and Tristate Buffers)

**Table 100 • Mini-LVDS AC Switching Characteristics for Transmitter (Output and Tristate Buffers)**

Worst-case Military Conditions:  $T_J = 125^\circ\text{C}$ ,  $V_{DD} = 1.14\text{ V}$ ,  $V_{DDI} = 2.375\text{ V}$

	Speed Grade -1					Units
	$t_{DP}$	$t_{ZL}$	$t_{ZH}$	$t_{HZ}$	$t_{LZ}$	
Mini-LVDS (for MSIO I/O Bank)	2.3	2.602	2.59	2.306	2.32	ns
<b>Mini-LVDS (for MSIOD I/O Bank)</b>						
No pre-emphasis	1.652	1.84	1.833	1.988	1.965	ns
Min pre-emphasis	1.652	1.84	1.833	1.988	1.965	ns
Med pre-emphasis	1.577	1.868	1.86	2.02	1.994	ns
Max pre-emphasis	1.555	1.894	1.883	2.048	2.019	ns

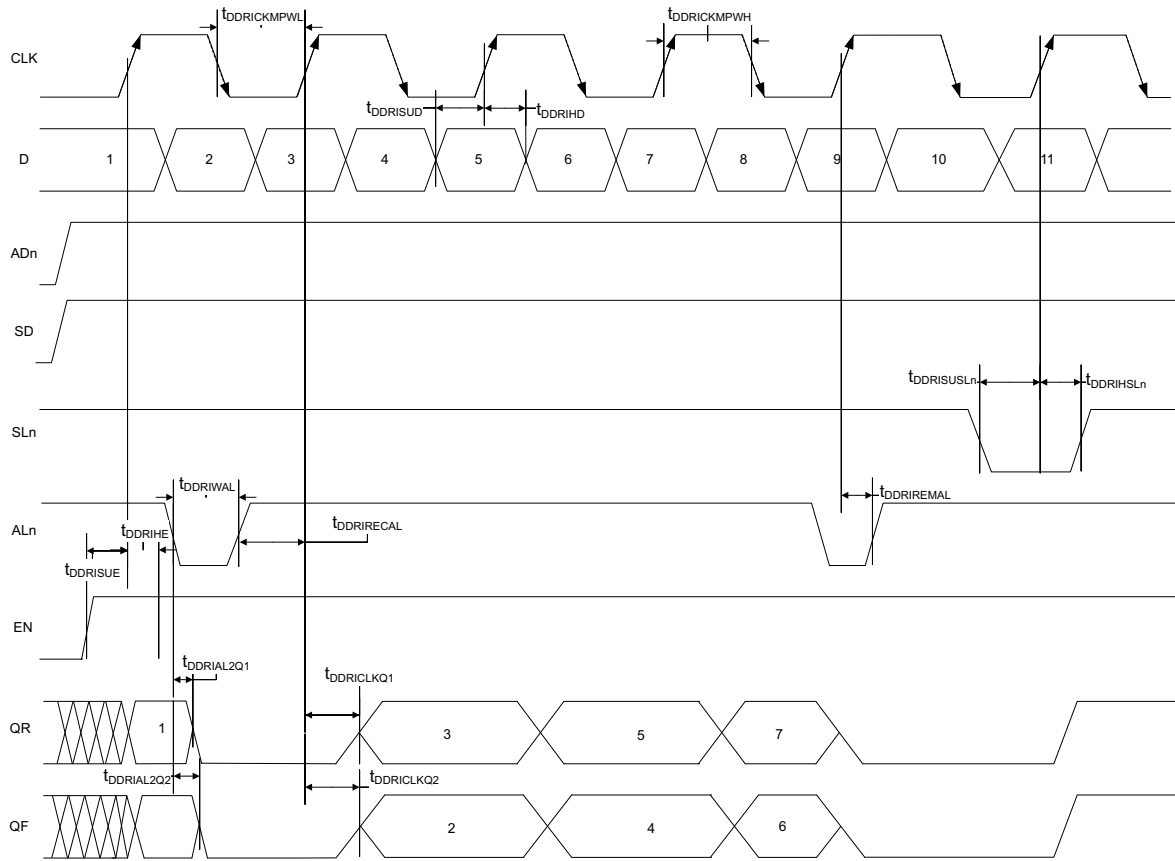


**Figure 6 • I/O Register Input Timing Diagram**

**Table 108 • Input Data Register Propagation Delays**  
Worst-Case Military Conditions:  $T_J = 125^\circ\text{C}$ ,  $V_{DD} = 1.14\text{ V}$

Parameter	Description	Measuring Nodes (from, to)*	Speed Grade -1	Units
$t_{\text{BYP}}$	Bypass Delay of the Input Register	F,G	0.364	ns
$t_{\text{CLKQ}}$	Clock-to-Q of the Input Register	E,G	0.165	ns
$t_{\text{SUD}}$	Data Setup Time for the Input Register	A,E	0.369	ns
$t_{\text{iHD}}$	Data Hold Time for the Input Register	A,E	0	ns
$t_{\text{iSUE}}$	Enable Setup Time for the Input Register	B,E	0.475	ns
$t_{\text{iHE}}$	Enable Hold Time for the Input Register	B,E	0	ns
$t_{\text{iSUSL}}$	Synchronous Load Setup Time for the Input Register	D,E	0.475	ns
$t_{\text{iHSL}}$	Synchronous Load Hold Time for the Input Register	D,E	0	ns
$t_{\text{iALn2Q}}$	Asynchronous Clear-to-Q of the Input Register ( $\text{ADn}=1$ )	C,G	0.648	ns
	Asynchronous Preset-to-Q of the Input Register ( $\text{ADn}=0$ )	C,G	0.606	ns

### 8.10.2 Input DDR Timing Diagram



**Figure 10 • Input DDR Timing Diagram**

**Table 122 • RAM1K18 – Dual-Port Mode for Depth x Width Configuration 8Kx2**

 Worst-Case Military Conditions:  $T_J = 125^{\circ}\text{C}$ ,  $V_{DD} = 1.14\text{ V}$  (continued)

Parameter	Description	Speed Grade -1		Units
		Min	Max	
tdsu	Data Setup Time	0.34	–	ns
tdhd	Data Hold Time	0.084	–	ns
tblksu	Block Select Setup Time	0.214	–	ns
tblkhd	Block Select Hold Time	0.223	–	ns
tblk2q	Block Select to Out Disable Time (when Pipe-Lined Registered is Disabled)	–	1.56	ns
tblkmpw	Block Select Minimum Pulse Width	0.218	–	ns
trdesu	Read Enable Setup Time	0.546	–	ns
trdehd	Read Enable Hold Time	0.073	–	ns
trdple su	Pipelined Read Enable Setup Time (A_DOUT_EN, B_DOUT_EN)	0.256	–	ns
trdplehd	Pipelined Read Enable Hold Time (A_DOUT_EN, B_DOUT_EN)	0.106	–	ns
tr2q	Asynchronous Reset to Output Propagation Delay	–	1.583	ns
trstrem	Asynchronous Reset Removal Time	0.522	–	ns
trstrec	Asynchronous Reset Recovery Time	0.005	–	ns
trstmpw	Asynchronous Reset Minimum Pulse Width	0.352	–	ns
tplrstrem	Pipelined Register Asynchronous Reset Removal Time	-0.288	–	ns
tplrstrec	Pipelined Register Asynchronous Reset Recovery Time	0.338	–	ns
tplrstmpw	Pipelined Register Asynchronous Reset Minimum Pulse Width	0.33	–	ns
tsrst su	Synchronous Reset Setup Time	0.233	–	ns
tsrsthd	Synchronous Reset Hold Time	0.037	–	ns
twe su	Write Enable Setup Time	0.504	–	ns
twehd	Write Enable Hold Time	0.05	–	ns
Fmax	Maximum Frequency	–	300	MHz

**Table 123 • RAM1K18 – Dual-Port Mode for Depth x Width Configuration 16Kx1**

 Worst-Case Military Conditions:  $T_J = 125^{\circ}\text{C}$ ,  $V_{DD} = 1.14\text{ V}$ 

Parameter	Description	Speed Grade -1		Units
		Min	Max	
tcy	Clock Period	3.333	–	ns
tclkmpwh	Clock Minimum Pulse Width High	1.5	–	ns
tclkmpwl	Clock Minimum pulse Width Low	1.5	–	ns
tpcy	Pipelined Clock Period	3.333	–	ns
tpclkmpwh	Pipelined Clock Minimum Pulse Width High	1.5	–	ns



**Table 123 • RAM1K18 – Dual-Port Mode for Depth x Width Configuration 16Kx1**

 Worst-Case Military Conditions:  $T_J = 125^{\circ}\text{C}$ ,  $V_{DD} = 1.14\text{ V}$  (continued)

Parameter	Description	Speed Grade -1		Units
		Min	Max	
tpclkmpwl	Pipelined Clock Minimum pulse Width Low	1.5	–	ns
tclk2q	Read Access Time with Pipeline Register	–	0.332	ns
	Read Access Time without Pipeline Register	–	2.342	ns
	Access Time with Feed-Through Write Timing	–	1.559	ns
taddrsu	Address Setup Time	0.646	–	ns
taddrhd	Address Hold Time	0.282	–	ns
tdsu	Data Setup Time	0.332	–	ns
tdhd	Data Hold Time	0.084	–	ns
tblksu	Block Select Setup Time	0.214	–	ns
tblkhd	Block Select Hold Time	0.223	–	ns
tblk2q	Block Select to Out Disable Time (when Pipe-Lined Registered is Disabled)	–	1.559	ns
tblkmpw	Block Select Minimum Pulse Width	0.218	–	ns
trdesu	Read Enable Setup Time	0.547	–	ns
trdehd	Read Enable Hold Time	0.073	–	ns
trdpleSU	Pipelined Read Enable Setup Time (A_DOUT_EN, B_DOUT_EN)	0.256	–	ns
trdplehd	Pipelined Read Enable Hold Time (A_DOUT_EN, B_DOUT_EN)	0.106	–	ns
tr2q	Asynchronous Reset to Output Propagation Delay		1.603	ns
trstrem	Asynchronous Reset Removal Time	0.522	–	ns
trstrec	Asynchronous Reset Recovery Time	0.005	–	ns
trstmpw	Asynchronous Reset Minimum Pulse Width	0.352	–	ns
tplrstrem	Pipelined Register Asynchronous Reset Removal Time	-0.288	–	ns
tplrstrec	Pipelined Register Asynchronous Reset Recovery Time	0.338	–	ns
tplrstmpw	Pipelined Register Asynchronous Reset Minimum Pulse Width	0.33	–	ns
tsrstsu	Synchronous Reset Setup Time	0.233	–	ns
tsrsthd	Synchronous Reset Hold Time	0.037	–	ns
twesu	Write Enable Setup Time	0.468	–	ns
twehd	Write Enable Hold Time	0.05	–	ns
Fmax	Maximum Frequency	–	300	MHz

**Table 130 • uSRAM (RAM512x2) in 512x2 Mode**  
 Worst-Case Military Conditions:  $T_J = 125^{\circ}\text{C}$ ,  $V_{DD} = 1.14\text{ V}$  (continued)

Parameter	Description	Speed Grade -1		Units
		Min	Max	
tclkmpwl	Read Clock Minimum pulse Width Low	1.8	–	ns
tpicy	Read Pipe-line clock period	4	–	ns
tpclkmpwh	Read Pipe-line clock Minimum Pulse Width High	1.8	–	ns
tpclkmpwl	Read Pipe-line clock Minimum Pulse Width Low	1.8	–	ns
tclk2q	Read Access Time with Pipeline Register	–	0.276	ns
	Read Access Time without Pipeline Register	–	1.824	ns
taddrsu	Read Address Setup Time in Synchronous Mode	0.311	–	ns
	Read Address Setup Time in Asynchronous Mode	2.023	–	ns
taddrhd	Read Address Hold Time in Synchronous Mode	0.141	–	ns
	Read Address Hold Time in Asynchronous Mode	-0.599	–	ns
trdensu	Read Enable Setup Time	0.287	–	ns
trdenhd	Read Enable Hold Time	0.059	–	ns
tblksu	Read Block Select Setup Time	1.898	–	ns
tblkhd	Read Block Select Hold Time	-0.671	–	ns
tblk2q	Read Block Select to Out Disable Time (when Pipe-Lined Registered is Disabled)	–	2.219	ns
trstrem	Read Asynchronous Reset Removal Time (Pipelined Clock)	-0.15	–	ns
	Read Asynchronous Reset Removal Time (Non-Pipelined Clock)	0.047	–	ns
trstrec	Read Asynchronous Reset Recovery Time (Pipelined Clock)	0.524	–	ns
	Read Asynchronous Reset Recovery Time (Non-Pipelined Clock)	0.244	–	ns
tr2q	Read Asynchronous Reset to Output Propagation Delay (With Pipe-Line Register Enabled)	–	0.862	ns
tsrstsu	Read Synchronous Reset Setup Time	0.279	–	ns
tsrsthd	Read Synchronous Reset Hold Time	0.062	–	ns
tccy	Write Clock Period	4	–	ns
tcclkmpwh	Write Clock Minimum Pulse Width High	1.8	–	ns
tcclkmpwl	Write Clock Minimum Pulse Width Low	1.8	–	ns
tblksu	Write Block Setup Time	0.417	–	ns
tblkchd	Write Block Hold Time	0.007	–	ns
tdincsu	Write Input Data setup Time	0.104	–	ns
tdinchd	Write Input Data hold Time	0.142	–	ns
taddrcsu	Write Address Setup Time	0.091	–	ns

## 13. Crystal Oscillator

Table 134 describes the electrical characteristics of the crystal oscillator in the IGLOO2 FPGA and SmartFusion2 SoC FPGAs.

**Table 134 • Electrical Characteristics of the Crystal Oscillator – High Gain Mode (20 MHz)**

Worst-Case Military Conditions:  $T_J = 125^\circ\text{C}$ ,  $V_{DD} = 1.14\text{ V}$

Parameter	Description	Min	Typ	Max	Units
FXTAL	Operating frequency	–	20	–	MHz
ACCXTAL	Accuracy	–	–	0.006	%
CYCXTAL	Output duty cycle	–	49-51	47-53	%
JITPERXTAL	Output Period Jitter (peak to peak)	–	200	300	ps
JITCYCXTAL	Output Cycle to Cycle Jitter (peak to peak)	–	200	550	ps
IDYNXTAL	Operating current	–	1.5	–	mA
VIHXTAL	Input logic level High	$0.9 \times V_{PP}$	–	–	V
VILXTAL	Input logic level Low	–	–	$0.1 \times V_{PP}$	V
SUXTAL	Startup time (with regard to stable oscillator output)	–	–	1	ms

**Table 135 • Electrical Characteristics of the Crystal Oscillator – Medium Gain Mode (2 MHz)**

Worst-Case Military Conditions:  $T_J = 125^\circ\text{C}$ ,  $V_{DD} = 1.14\text{ V}$

Parameter	Description	Min	Typ	Max	Units
FXTAL	Operating frequency	–	2	–	MHz
ACCXTAL	Accuracy	–	–	0.003	%
CYCXTAL	Output duty cycle	–	49–51	47–53	%
JITPERXTAL	Output Period Jitter (peak to peak)	–	1	5	ns
JITCYCXTAL	Output Cycle to Cycle Jitter (peak to peak)	–	1	5	ns
IDYNXTAL	Operating current	–	0.3	–	mA
VIHXTAL	Input logic level High	$0.9 \times V_{PP}$	–	–	V
VILXTAL	Input logic level Low	–	–	$0.1 \times V_{PP}$	V
SUXTAL	Startup time (with regard to stable oscillator output)	–	–	4.5	ms

**Table 136 • Electrical Characteristics of the Crystal Oscillator – Low Gain Mode (32 kHz)**

Worst-Case Military Conditions:  $T_J = 125^\circ\text{C}$ ,  $V_{DD} = 1.14\text{ V}$

Parameter	Description	Min	Typ	Max	Units
FXTAL	Operating frequency	–	32	–	kHz
ACCXTAL	Accuracy	–	–	0.006	%
CYCXTAL	Output duty cycle	–	49–51	45.5–54.5	%
JITPERXTAL	Output Period Jitter (peak to peak)	–	150	300	ns
JITCYCXTAL	Output Cycle to Cycle Jitter (peak to peak)	–	150	300	ns

## 18. System Controller SPI Characteristics

**Table 143 • System Controller SPI Characteristics**

 Worst-Case Military Conditions:  $T_J = 125^{\circ}\text{C}$ ,  $V_{DD} = 1.14\text{ V}$ 

Symbol	Description	Conditions	All Devices/Speed Grades			Units	Notes
			Min	Typ	Max		
sp1	SC_SPI_SCK minimum period	–	20	–	–	ns	–
sp2	SC_SPI_SCK minimum pulse width high	–	10	–	–	ns	–
sp3	SC_SPI_SCK minimum pulse width low	–	10	–	–	ns	–
sp4	SC_SPI_SCK, SC_SPI_SDO, SC_SPI_SS rise time (10%-90%) 1	I/O Configuration: LVTTTL 3.3V- 20mA AC Loading: 35pF Test Conditions: Typical Voltage, 25C	–	1.239	–	ns	*
sp5	SC_SPI_SCK, SC_SPI_SDO, SC_SPI_SS fall time (10%-90%) 1	I/O Configuration: LVTTTL 3.3V- 20mA AC Loading: 35pF Test Conditions: Typical Voltage, 25C	–	1.245	–	ns	*
sp6	Data from master (SC_SPI_SDO) setup time	–	160	–	–	ns	–
sp7	Data from master (SC_SPI_SDO) hold time	–	160	–	–	ns	–
sp8	SC_SPI_SDI setup time	–	20	–	–	ns	–
sp9	SC_SPI_SDI hold time	–	20	–	–	ns	–

*Note: \*For specific Rise/Fall Times, board design considerations and detailed output buffer resistances, use the corresponding IBIS models located on the Microsemi SoC Products Group website: <http://www.microsemi.com/products/fpga-soc/design-resources/ibis-models>. Use the supported I/O Configurations for the System Controller SPI in Table 144.*

**Table 144 • Supported I/O Configurations for System Controller SPI (for MSIO Bank Only)**

Voltage Supply	I/O Drive Configuration	Units
3.3 V	20	mA
2.5 V	16	mA
1.8 V	12	mA
1.5 V	8	mA
1.2 V	4	mA

**Table 158 • I2C Characteristics**  
Worst-Case Military Conditions:  $T_J = 125^\circ\text{C}$ ,  $V_{DD} = 1.14\text{ V}$  (continued)

Parameter	Definition	Conditions	Min	Typ	Max	Units	Notes
VHYS	Hysteresis of Schmitt triggered inputs for $V_{DDI} > 2\text{ V}$	Refer to Table 20 on page 27 for more information.	$0.05 \times V_{DDI}$	–	–	V	–
IIL	Input current high	Refer to the "Single-Ended I/O Standards" section on page 27 for more information.	–	–	10	$\mu\text{A}$	–
IIH	Input current low	Refer to the "Single-Ended I/O Standards" section on page 27 for more information.	–	–	10	$\mu\text{A}$	–
Tir	Input rise time	Standard Mode	–	–	1000	ns	–
–	–	Fast Mode	–	–	300	ns	–
Tif	Input fall time	Standard Mode	–	–	300	ns	–
–	–	Fast Mode	–	–	300	ns	–
VOL	Maximum output voltage low (open drain) at 3 mA sink current for $V_{DDI} > 2\text{ V}$	Refer to the "Single-Ended I/O Standards" section on page 27 for more information. I/O standard used for illustration: MSIO bank – LVTTTL 8 mA low drive.	–	–	0.4	V	–
Cin	Pin capacitance	$V_{IN} = 0$ , $f = 1.0\text{ MHz}$	–	–	10	pF	–
$t_{OF}$	Output fall time from $V_{IHMin}$ to $V_{ILMax}$	$V_{IHmin}$ to $V_{ILMax}$ , $C_{load} = 400\text{ pF}$	–	21.04	–	ns	1
		$V_{IHmin}$ to $V_{ILMax}$ , $C_{load} = 100\text{ pF}$	–	5.556	–	ns	
$t_{OR}$	Output rise time from $V_{ILMax}$ to $V_{IHMin}$	$V_{ILMax}$ to $V_{IHmin}$ , $C_{load} = 400\text{ pF}$	–	19.887	–	ns	1
		$V_{ILMax}$ to $V_{IHmin}$ , $C_{load} = 100\text{ pF}$	–	5.218	–	ns	
Rpull-up	Output maximum pull-down resistance	–	–	–	50	$\Omega$	2, 3
Rpull-down	Output maximum pull-up resistance	–	–	–	131.25	$\Omega$	2, 4
Dmax	Maximum data rate	Fast mode	–	–	400	Kbps	–
		Standard mode	–	–	100	Kbps	–
$t_{FILT}$	Pulse width of spikes which must be suppressed by the input filter	Fast mode	–	50	–	ns	–

**Notes:**

1. These values are provided for MSIO Bank - LVTTTL 8 mA Low Drive at  $25^\circ\text{C}$ , typical conditions. For Board Design considerations and detailed output buffer resistances, use the corresponding IBIS models located on the SoC Products Group website: <http://www.microsemi.com/products/fpga-soc/design-resources/ibis-models>.
2. These maximum values are provided for information only. Minimum output buffer resistance values depend on  $V_{DDI}$ , drive strength selection, temperature, and process. For board design considerations and detailed output buffer resistances, use the corresponding IBIS models located on the SoC Products Group website: <http://www.microsemi.com/products/fpga-soc/design-resources/ibis-models>.
3.  $R(\text{PULL-DOWN-MAX}) = (V_{OLspec}) / I_{OLspec}$
4.  $R(\text{PULL-UP-MAX}) = (V_{DDImax} - V_{OHspec}) / I_{OHspec}$